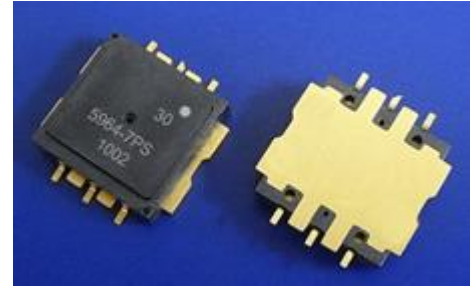


■ Features

- High Output Power: P1dB=39.0dBm (Typ.)
- High Gain: G1dB=11.0dB (Typ.)
- High Power Added Efficiency : PAE=36% (Typ.)
- Broad Band: Frequency= 5.9 to 6.4GHz
- Internally Matched
- Plastic Package for SMT applications



■ Description

The ELM5964-7PS is a power GaAs FET that is internally matched for standard communication bands to provide optimum power and gain.

ABSOLUTE MAXIMUM RATING (Case Temperature T_c=25 deg.C)

Item	Symbol	Rating	Unit
Drain-Source Voltage	V _{DS}	15	V
Gate-Source Voltage	V _{GS}	-5	V
Total Power Dissipation	P _T	50	W
Storage Temperature	T _{stg}	-40 to +125	deg.C
Channel Temperature	T _{ch}	175	deg.C

RECOMMENDED OPERATING CONDITION

Item	Symbol	Condition	Limit	Unit
Drain-Source Voltage	V _{DS}		<10	V
Forward Gate Current	I _{GF}	Rg=100ohm	<+16	mA
Reverse Gate Current	I _{GR}	Rg=100ohm	> -2.2	mA
Channel Temperature	T _{ch}		155	deg.C

ELECTRICAL CHARACTERISTICS (Case Temperature T_c=25 deg.C)

Item	Symbol	Condition	Limit			Unit
			Min.	Typ.	Max.	
Saturated Drain Current	I _{DSS}	VDS=5V, VGS=0V	-	3400	5200	mA
Trans Conductance	g _m	VDS=5V, IDS=2200mA	-	3400	-	mS
Pinch-off Voltage	V _p	VDS=5V, IDS=170mA	-0.5	-1.5	-3.0	V
Gate-Source Breakdown Voltage	V _{GSO}	IGS=-170uA	-5.0	-	-	V
Output Power at 1dB G.C.P.	P _{1dB}	VDS=10V Ids(DC)=2200mA(typ.) f=5.9 to 6.4 GHz	38.0	39.0	-	dBm
Power Gain at 1dB G.C.P.	G _{1dB}		9.5	11.0	-	dB
Drain Current	I _{DSR}		-	2200	2600	mA
Power Added Efficiency	PAE		-	36.0	-	%
Gain Flatness	ΔG		-	-	1.2	dB
3rd Order Inter Modulation Distortion	IM ₃	f=6.4GHz Δf=10MHz, 2-tone Test Pout=28.0dBm (S.C.L.)	-40.0	-45.0	-	dBc
Thermal Resistance	R _{th}	Channel to Case	-	2.5	3.0	deg.C/W
Channel Temperature Rise	ΔT _{ch}	(V _{DS} × I _{DSR} - Pout + Pin) × R _{th}	-	-	80.0	deg.C

G.C.P. : Gain Compression Point, S.C.L. : Single Carrier Level

CASE STYLE	I2C	
RoHS Compliance	YES	
ESD	Class 3A	4000V to < 8000V
MSL	2	One year after opening the packing

Note : Based on ANSI/ESDA/JEDEC JS-001-2012(C=100pF, R=1.5kohm)

Ordering Information

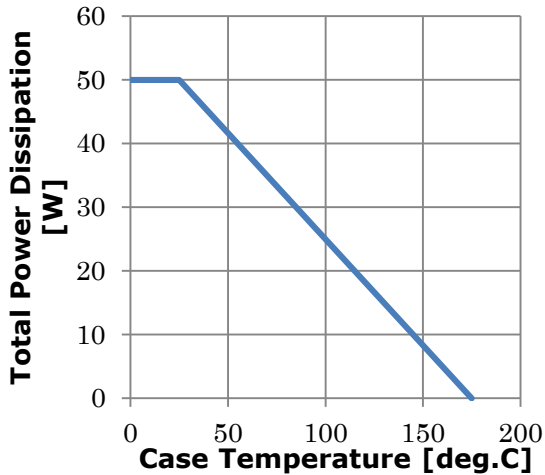
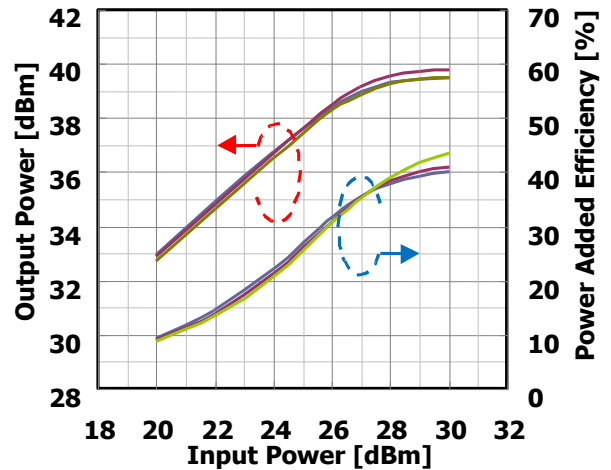
Model Type	MOQ	MOU	Packing Style
ELM5964-7PS	15pcs	15pcs	50pcs-max./Tray , 1Tray-max./Packing
ELM5964-7PST	500pcs	500pcs	24mm width Tape (500pcs/Reel)

* MOQ stands for Minimum Order Quantity.

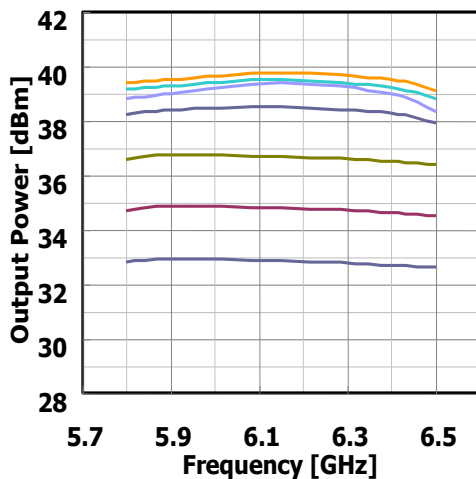
* MOU stands for Minimum Order Unit size.

Note

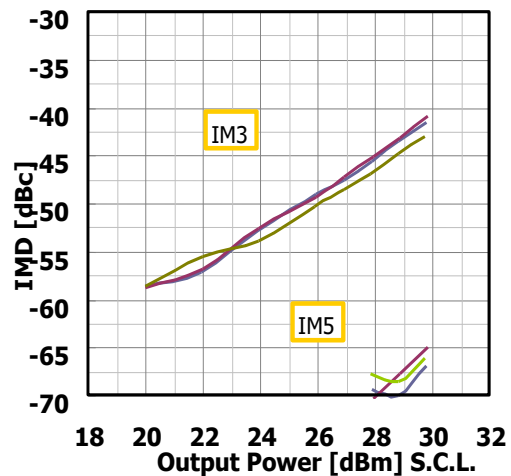
- This device will not be delivered with test data but tested pass/fail 100% against DC and RF specifications.
- NO liquid cleaning process is suitable for this device. (including de-ionized water or solvent)

● RF Characteristics
Power Derating Curve

Input Power vs. Output Power and Power Added Efficiency
 $V_{DS}=10V, I_{DS(DC)}=2200mA$


— 5.9 GHz — 6.15 GHz — 6.4 GHz

Output Power vs. Frequency
 $V_{DS}=10V, I_{DS(DC)}=2200mA$


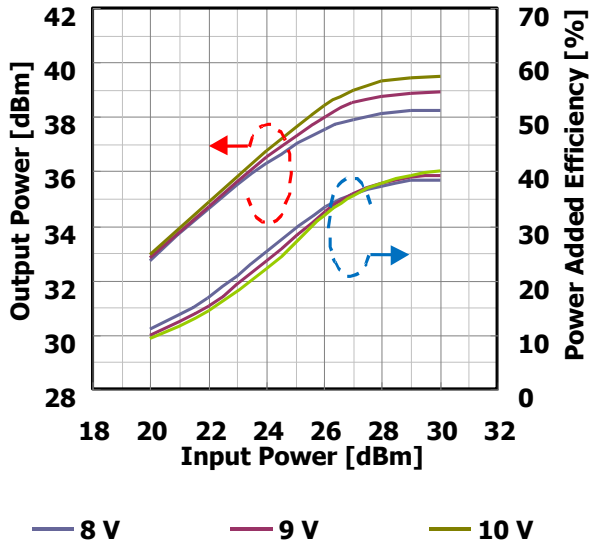
— 20 dBm — 22 dBm — 24 dBm — 26 dBm
 — 28 dBm — 30 dBm — P1dB

IMD vs. Output Power
 $V_{DS}=10V, I_{DS(DC)}=2200mA$


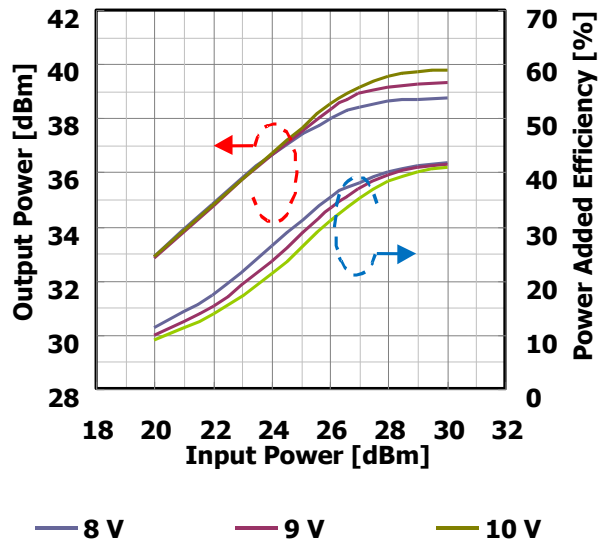
— 5.9 GHz — 6.15 GHz — 6.4 GHz

● RF Characteristics

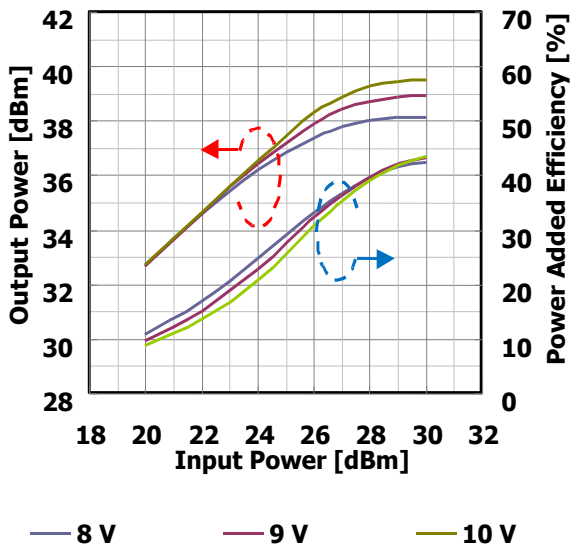
Input Power vs. Output Power, Power Added Efficiency by Drain Voltage
IDS(DC)=2200mA @5.9GHz

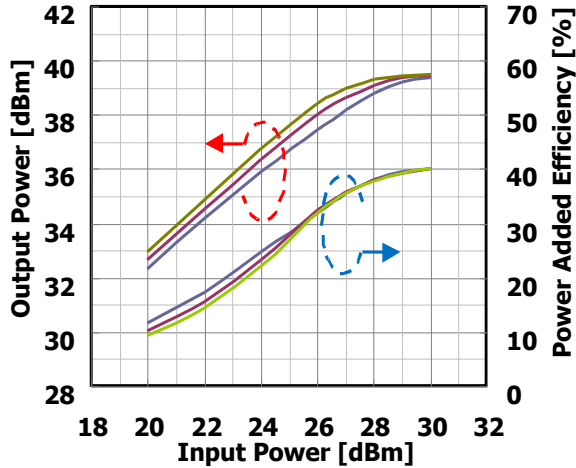


Input Power vs. Output Power, Power Added Efficiency by Drain Voltage
IDS(DC)=2200mA @6.15GHz

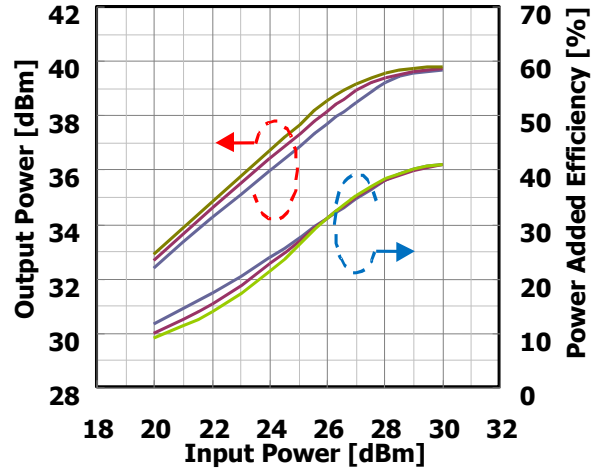


Input Power vs. Output Power, Power Added Efficiency by Drain Voltage
IDS(DC)=2200mA @6.4GHz

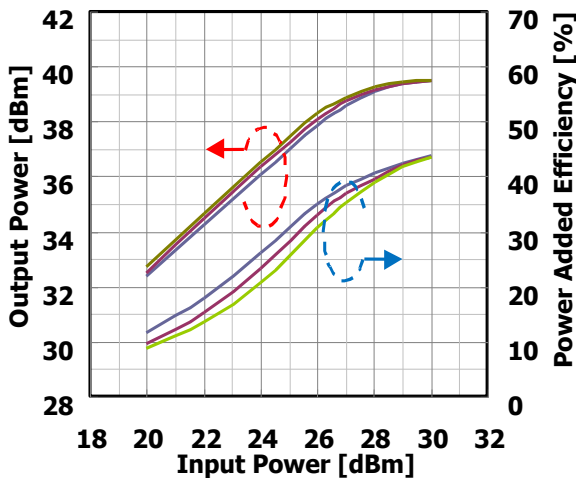


● RF Characteristics
**Input Power vs. Output Power, Power Added Efficiency by Quiescent Drain Current
VDS=10V @5.9GHz**


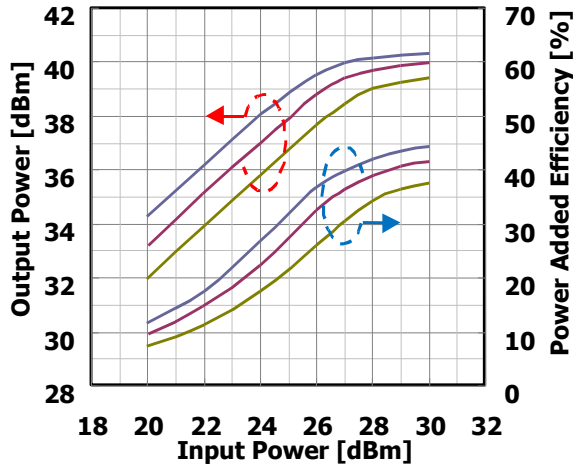
— 1400 mA — 1800 mA — 2200 mA

**Input Power vs. Output Power, Power Added Efficiency by Quiescent Drain Current
VDS=10V @6.15GHz**


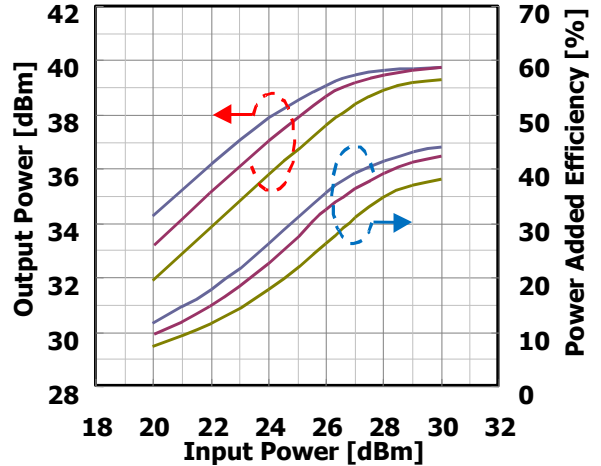
— 1400 mA — 1800 mA — 2200 mA

**Input Power vs. Output Power, Power Added Efficiency by Quiescent Drain Current
VDS=10V @6.4GHz**


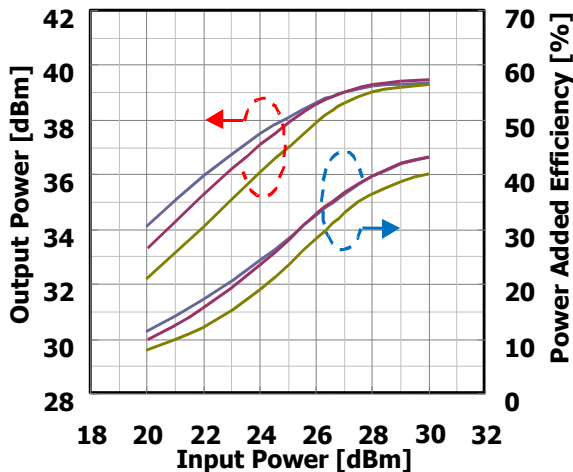
— 1400 mA — 1800 mA — 2200 mA

● RF Characteristics
Input Power vs. Output Power, Power Added Efficiency by Case Temperature
VDS=10V IDS(DC)=2200mA @5.9GHz


— -40 deg.C — 20 deg.C — 80 deg.C

Input Power vs. Output Power, Power Added Efficiency by Case Temperature
VDS=10V IDS(DC)=2200mA @6.15GHz


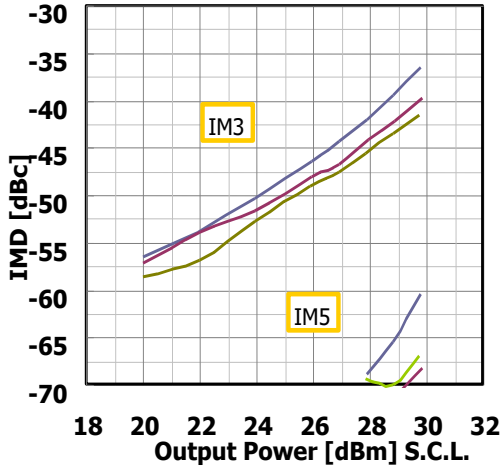
— -40 deg.C — 20 deg.C — 80 deg.C

Input Power vs. Output Power, Power Added Efficiency by Case Temperature
VDS=10V IDS(DC)=2200mA @6.4GHz


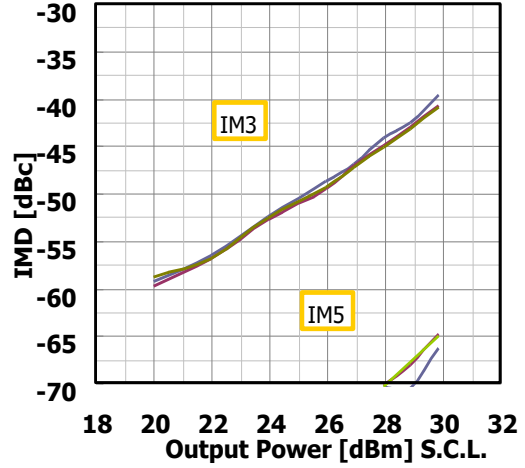
— -40 deg.C — 20 deg.C — 80 deg.C

● RF Characteristics

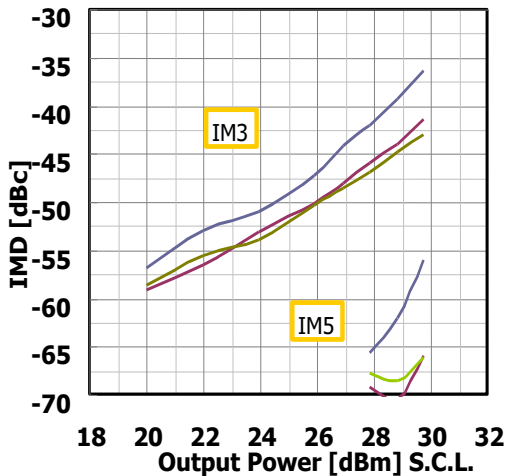
**IMD Performance vs. Output Power
by Drain Voltage**
 IDS(DC)=2200mA @5.9GHz

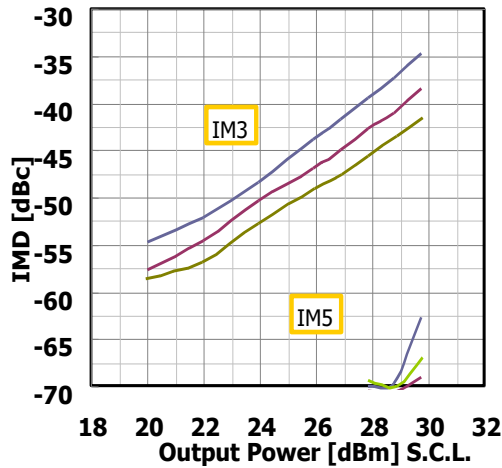


**IMD Performance vs. Output Power
by Drain Voltage**
 IDS(DC)=2200mA @6.15GHz

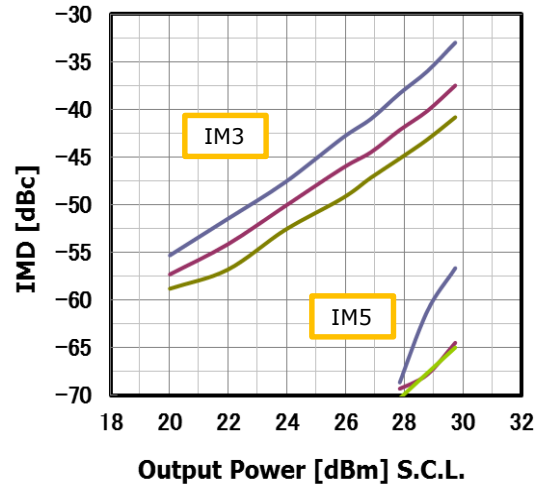


**IMD Performance vs. Output Power
by Drain Voltage**
 IDS(DC)=2200mA @6.4GHz

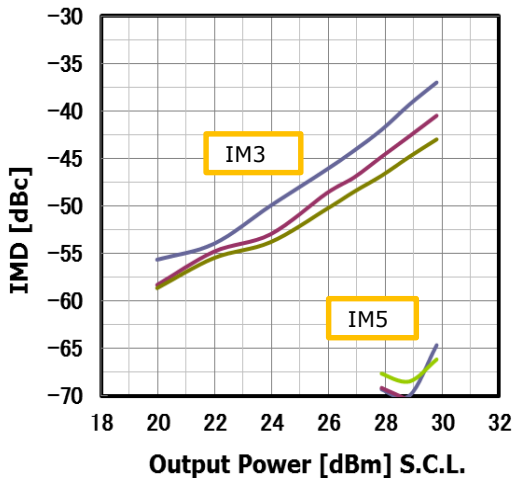


● RF Characteristics
IMD Performance vs. Output Power by Quiescent Drain Current
VDS=10V @5.9GHz


— 1400 mA — 1800 mA — 2200 mA

IMD Performance vs. Output Power by Quiescent Drain Current
VDS=10V @6.15GHz


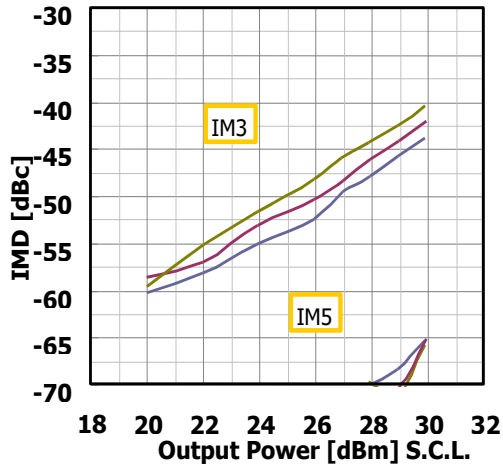
— 1400 mA — 1800 mA — 2200 mA

IMD Performance vs. Output Power by Quiescent Drain Current
VDS=10V @6.4GHz


— 1400 mA — 1800 mA — 2200 mA

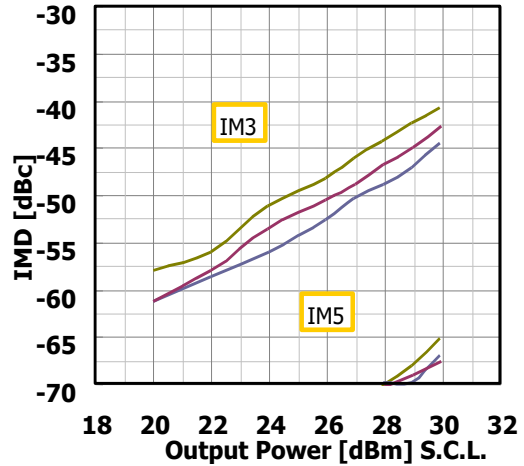
● RF Characteristics

**IMD Performance vs. Output Power
by Case Temperature**
VDS=10V IDS(DC)=2200mA @5.9GHz



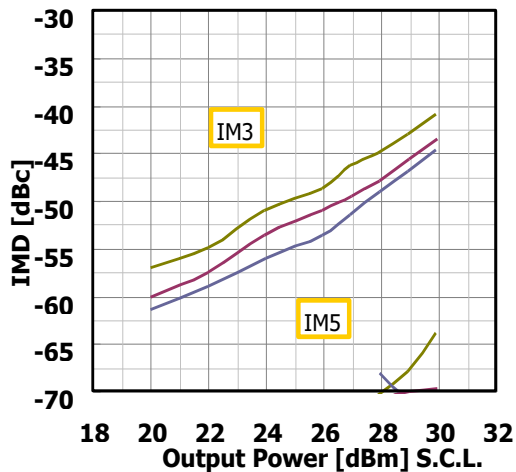
— -40 deg.C — 20 deg.C — 80 deg.C

**IMD Performance vs. Output Power
by Case Temperature**
VDS=10V IDS(DC)=2200mA @6.15GHz

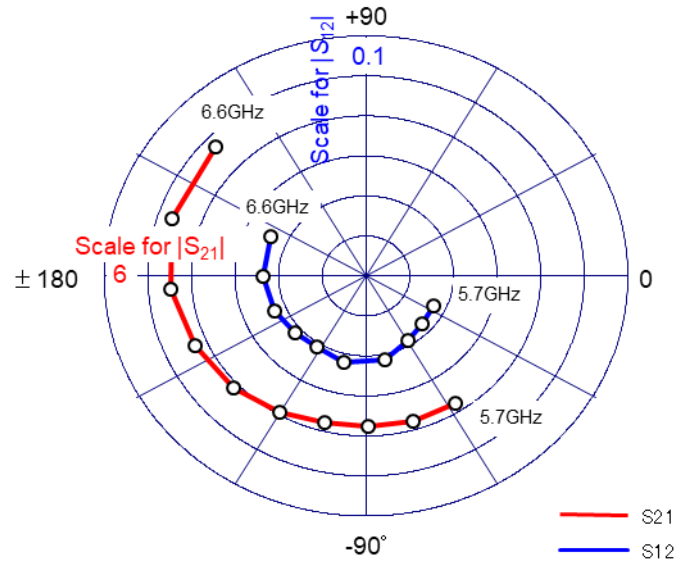
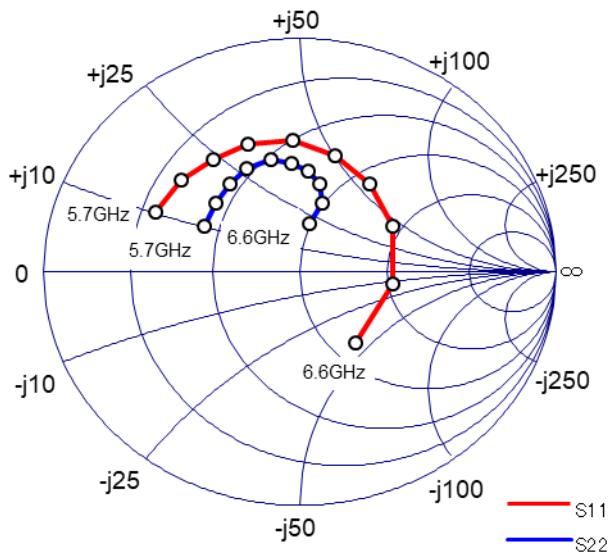


— -40 deg.C — 20 deg.C — 80 deg.C

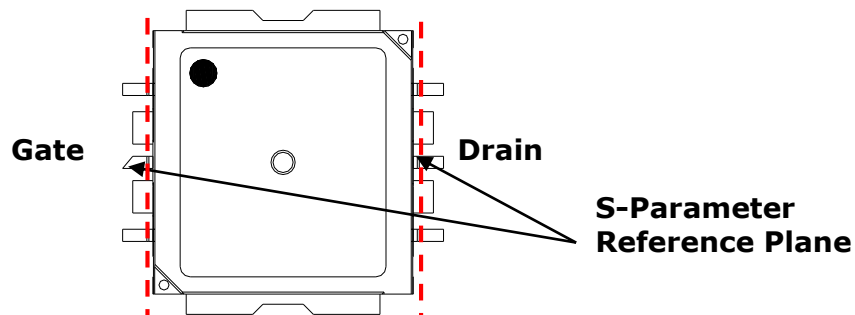
**IMD Performance vs. Output Power
by Case Temperature**
VDS=10V IDS(DC)=2200mA @6.4GHz

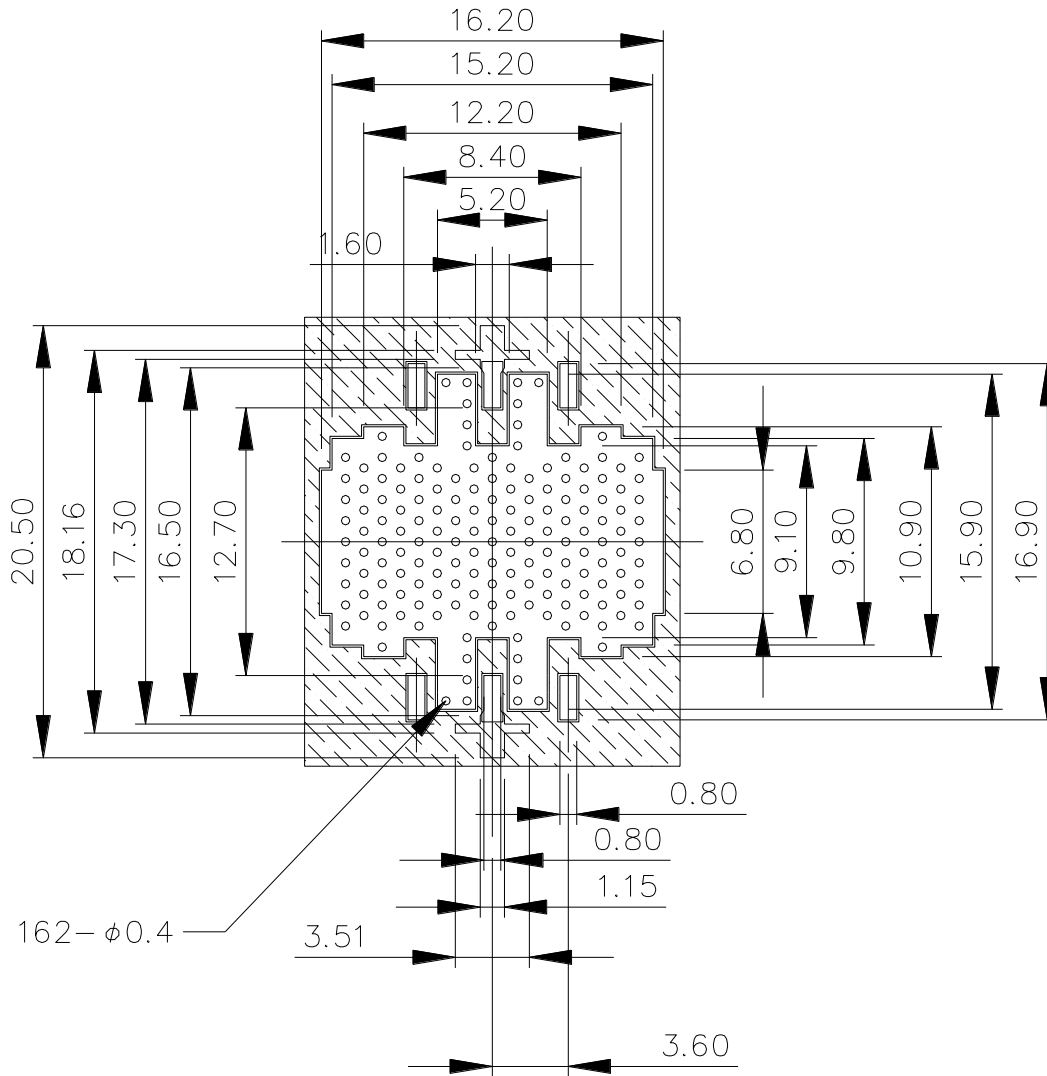


— -40 deg.C — 20 deg.C — 80 deg.C


● S-Parameter


Frequency (MHz)	S11		S21		S12		S22	
	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
5700	0.618	155.6	3.778	-57.4	0.029	-25.9	0.42	152.6
5800	0.607	139.7	3.782	-73.6	0.029	-43.4	0.442	138.1
5900	0.589	124.9	3.773	-89.3	0.031	-59.7	0.463	126
6000	0.582	110	3.789	-104.3	0.035	-78.1	0.486	114.9
6100	0.567	92.6	3.953	-120.1	0.037	-103.2	0.494	103.1
6200	0.519	74.3	4.12	-137.4	0.035	-122.3	0.467	93.6
6300	0.467	54	4.297	-155.9	0.036	-138.8	0.434	85.6
6400	0.413	28	4.485	-175.7	0.038	-157.7	0.384	78.2
6500	0.367	-8.1	4.678	162	0.04	-179.5	0.307	73.2
6600	0.374	-54.7	4.72	137.1	0.04	156	0.209	79.3

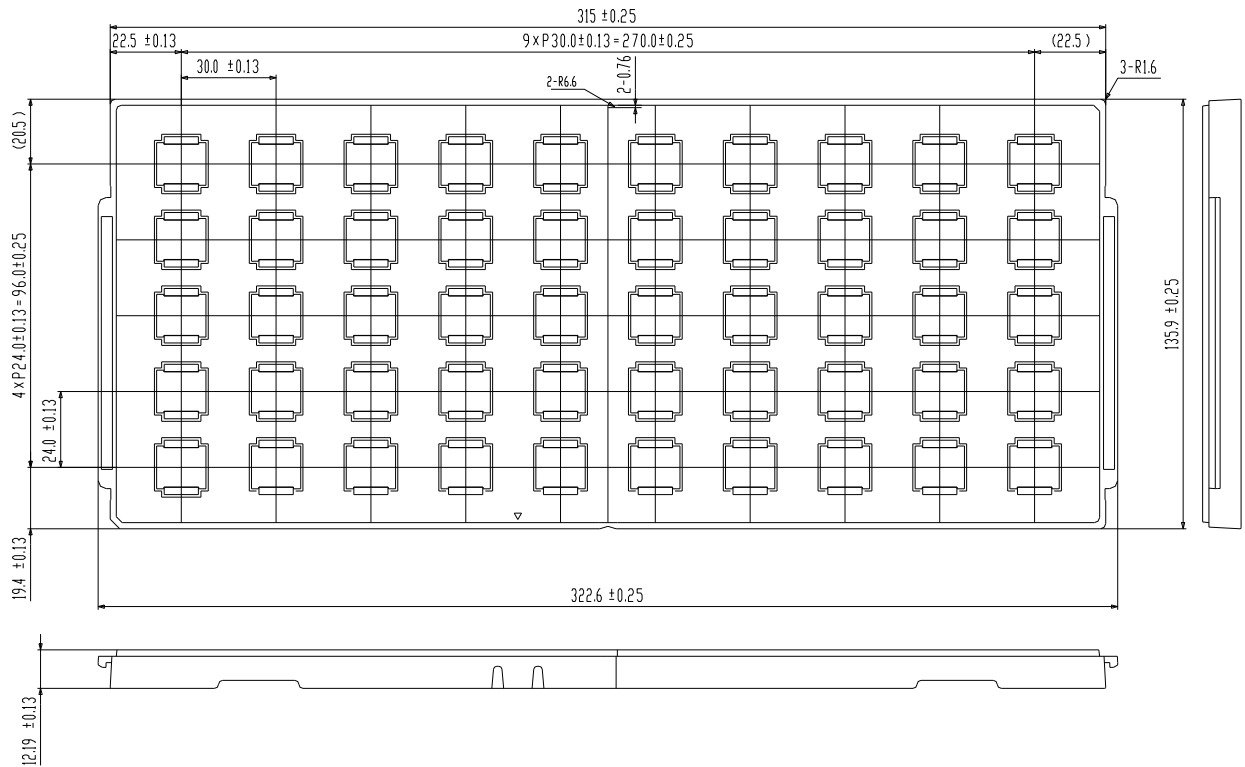


● PCB Pads and Solder-Resist Pattern


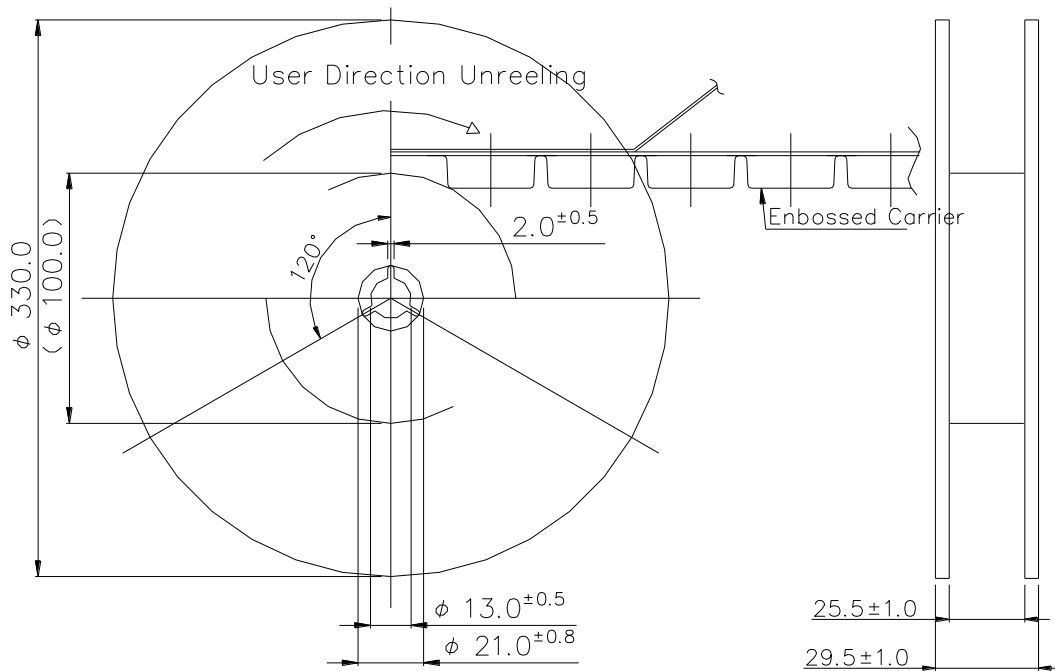
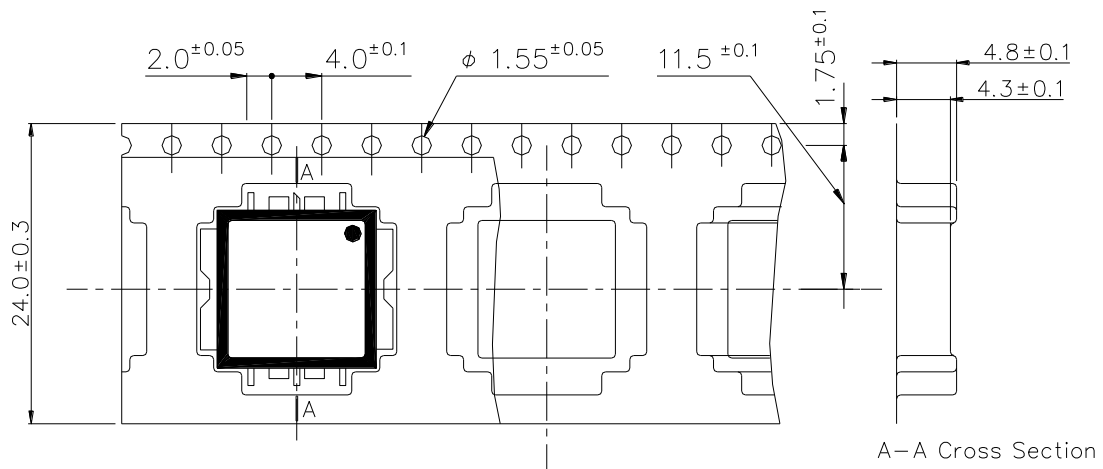
Notes :

1. Laminate : Rogers Corporation R04003, Thickness $t=0.508\text{mm}$, Cu Foil $18\mu\text{m}$.
 Finish to copper foil : Ni $0.1\mu\text{m}$ min. / Au $0.1\mu\text{m}$ (Both side).
2.  : Resist

- **JEDEC Tray Dimension
(Part No:ELM5964-7PS)**



● **Tape/Reel Configuration**
(Part No:ELM5964-7PST)



Quantity: 500pcs/tape
Tape Material: Conductive PS

(unit in mm)

● Mounting Instructions for Package for Lead-free solder

Mounting Condition

For soldering, Lead-free solder (Sn-3.0Ag-0.5Cu)*1 or equivalent shall be used.

1. The example solder is a tin-rich alloy with 3.0% silver and 0.5% copper, often called Sn 96 for its approximate Tin content.
2. A rosin type flux with chlorine content of 0.2% or less shall be used. The rosin flux with low halogen content is recommended. When soldering, use the following time/ temperature profile with any of the methods listed for acceptable solder joints.
3. Make sure the devices have been properly prepared with flux prior soldering.

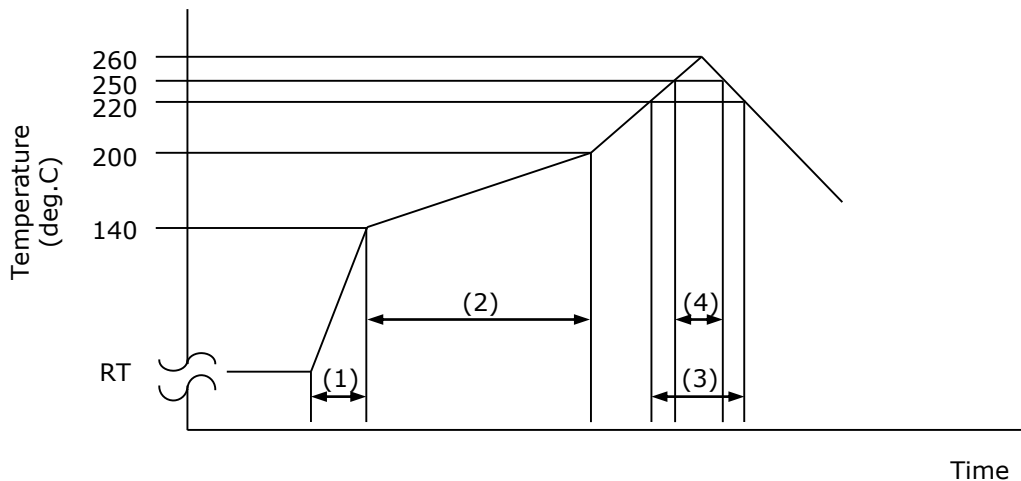
* Reflow soldering method (Infrared reflow / Heat circulation reflow / Hot plate reflow);

Limit solder to 3 reflow cycles because resin is used in the modules manufacturing process.

Excessive reflow will effect the resin resulting in a potential failure or latent defect.

The recommended reflow temperature profile is shown below. The temperature of the reflow profile must be measured at the device lead.

● Reflow temperature profile and condition:



- (1). Temperature rise: 3 deg.C/seconds.
 - (2). Preheating: 150 to 200 deg.C, 60 to 180seconds.
 - (3). Main heating: 220 deg.C, 60 seconds max.
 - (4). Main heating: 260 deg.C max., more than 250 deg.C, 20 to 40 seconds max.
- * Measurement point: Device Heat-sink (Source Pin).

1. The above-recommended conditions were confirmed using the manufacturer's equipment and materials. However, when soldering these products, the soldering condition should be verified by customer using their own particular equipment and materials.

● Cleaning

Avoid washing of the device after soldering by reflow method due to the risk of liquid absorption by the resin used in this part.

Humidity Lifetime for ELMxxxx-7PST

The following graph shows the effect of moisture on lifetime (moisture resistance) for the **ELMxxxx-7PST**. Each graph indicates the MTTF and failure rate prediction (Confidential Level = 90 %) which calculated from the results of highly accelerated temperature and humidity stress test (HAST).

Representative of device type : ELM7179-7PST

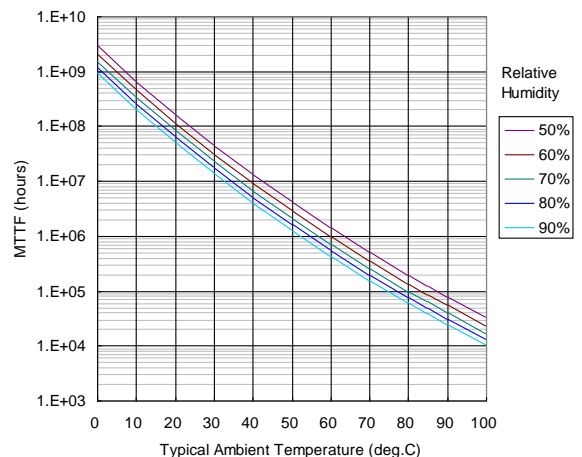
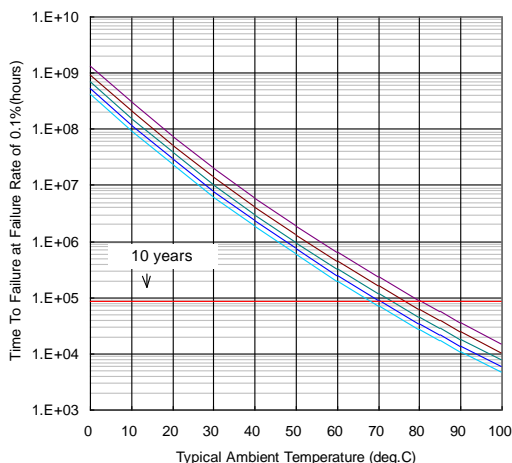
Subject of device type : ELMxxxx-7PST

Field environmental conditions for operation

If the **ELMxxxx-7PST** is installed in a non-hermetic environment, please refer to the following recommendations and notes for design with, and assembly and use of our products.

Note 1. When drain current cuts off, it should be cut off by drain bias, and not cut off by gate bias only. The humidity lifetime becomes shorter in case of the gate-only cut off operation due to electric field strength interacting with humidity.

Note 2. **ELMxxxx-7PST** should be used under the environment conditions of no dew condensation. These plots do not apply in the case of liquid absorbed into the resin, whether applied to the part in assembly or as condensate in the application.



For Safety, Observe the Following Procedures Environmental Management

- Do not put this product into the mouth.
- Do not alter the form of this product into a gas, powder, or liquid through burning, crushing, or chemical processing as these by-products are dangerous to the human body if inhaled, ingested, or swallowed.
- Respect all applicable laws of the country when discarding this product.
This product must be disposed in accordance with methods specified by applicable hazardous waste procedures.

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